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Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	50MHz
Connectivity	I ² C, LINbus, SCI, SPI
Peripherals	LVD, PWM, WDT
Number of I/O	34
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-LQFP
Supplier Device Package	44-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08qe128cld

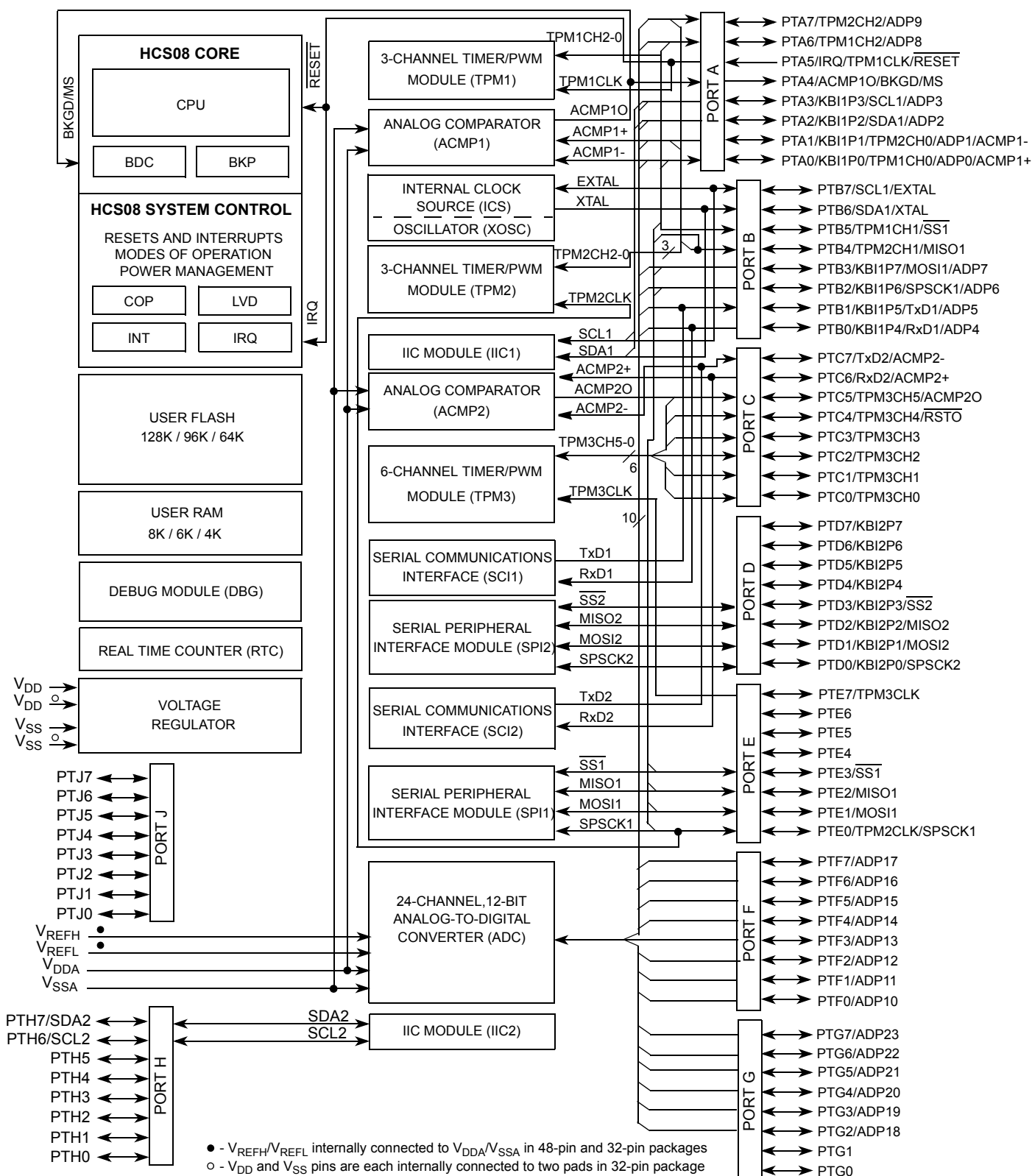


Figure 1. MC9S08QE128 Series Block Diagram

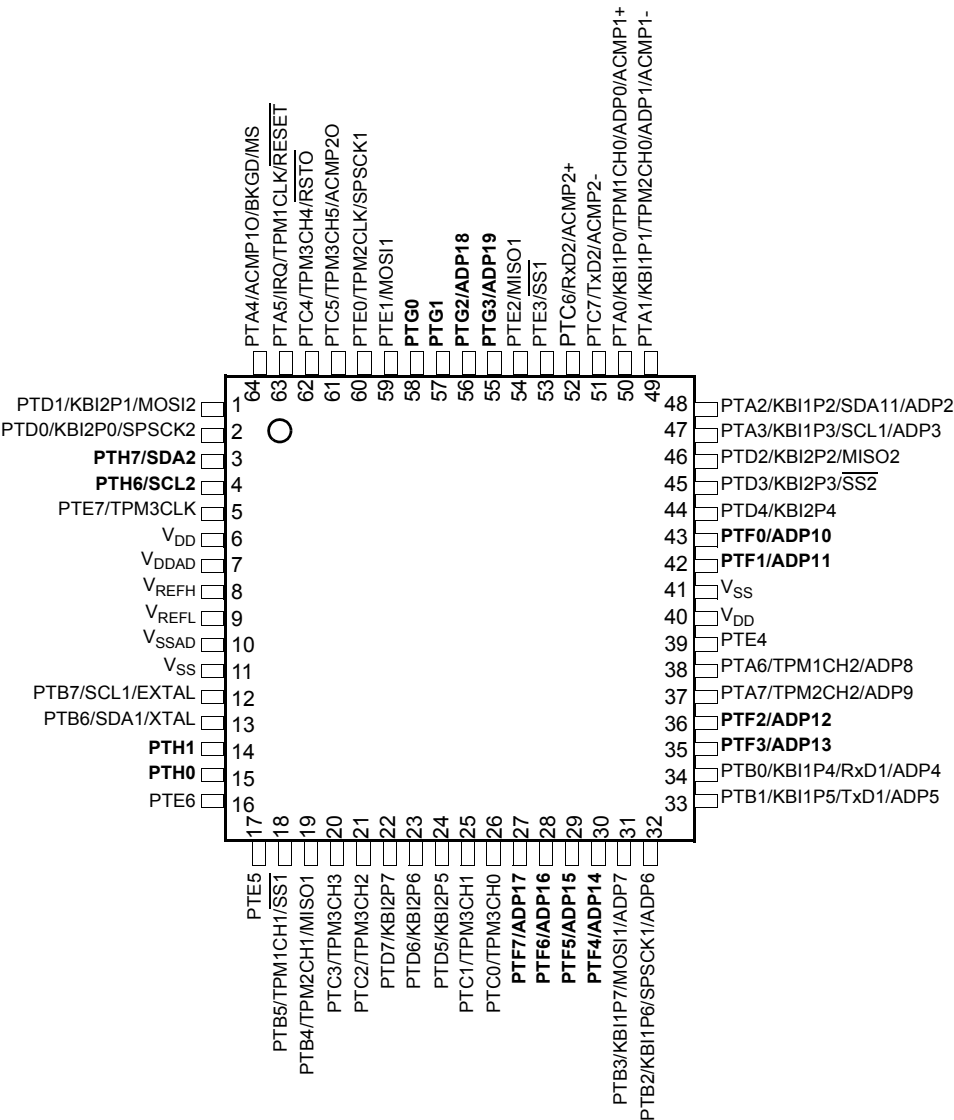
1 MC9S08QE128 Series Comparison

The following table compares the various device derivatives available within the MC9S08QE128 series.

Table 1. MC9S08QE128 Series Features by MCU and Package

Feature	MC9S08QE128				MC9S08QE96				MC9S08QE64			
Flash size (bytes)	131072				98304				65536			
RAM size (bytes)	8064				6016				4096			
Pin quantity	80	64	48	44	80	64	48	44	64	48	44	32
ACMP1	yes											
ACMP2	yes											
ADC channels	24	22	10	10	24	22	10	10	22	10	10	10
DBG	yes											
ICS	yes											
IIC1	yes											
IIC2	yes	yes	no	no	yes	yes	no	no	yes	no	no	no
IRQ	yes											
KBI	16	16	16	16	16	16	16	16	16	16	16	12
Port I/O ¹	70	54	38	34	70	54	38	34	54	38	34	26
RTC	yes											
SCI1	yes											
SCI2	yes											
SPI1	yes											
SPI2	yes											
TPM1 channels	3											
TPM2 channels	3											
TPM3 channels	6											
XOSC	yes											

¹ Port I/O count does not include the input only PTA5/IRQ/TPM1CLK/RESET or the output only PTA4/ACMP1O/BKGD/MS.



Pins in **bold** are added from the next smaller package.

Figure 3. Pin Assignments in 64-Pin LQFP Package

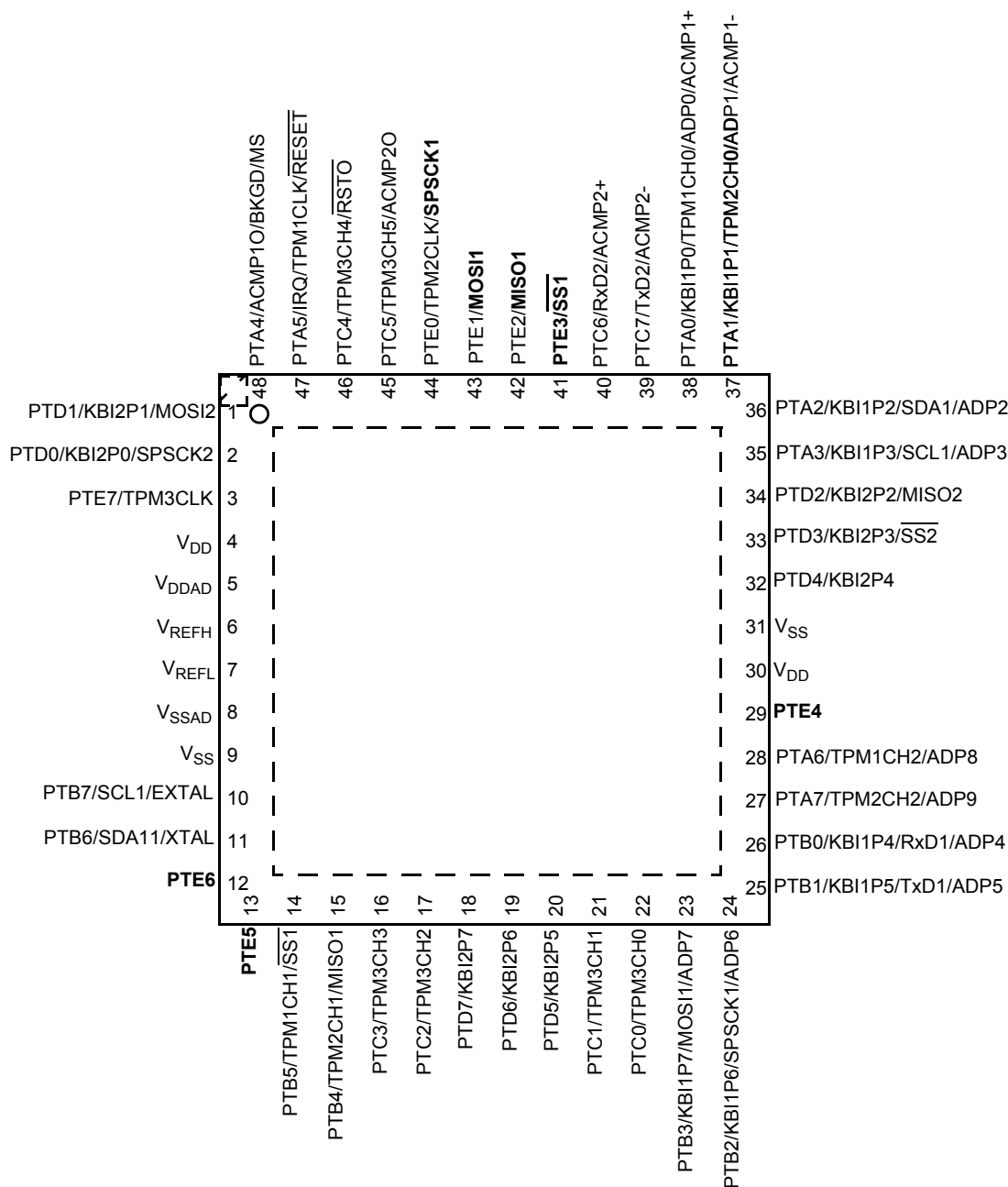


Figure 4. Pin Assignments in 48-Pin QFN Package

3 Electrical Characteristics

3.1 Introduction

This section contains electrical and timing specifications for the MC9S08QE128 series of microcontrollers available at the time of publication.

3.2 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table 3. Parameter Classifications

P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

3.3 Absolute Maximum Ratings

Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the limits specified in Table 4 may affect device reliability or cause permanent damage to the device. For functional operating conditions, refer to the remaining tables in this section.

This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for instance, either V_{SS} or V_{DD}) or the programmable pull-up resistor associated with the pin is enabled.

Table 4. Absolute Maximum Ratings

Rating	Symbol	Value	Unit
Supply voltage	V_{DD}	−0.3 to +3.8	V
Maximum current into V_{DD}	I_{DD}	120	mA
Digital input voltage	V_{In}	−0.3 to $V_{DD} + 0.3$	V
Instantaneous maximum current Single pin limit (applies to all port pins) ^{1, 2, 3}	I_D	± 25	mA
Storage temperature range	T_{stg}	−55 to 150	°C

¹ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive (V_{DD}) and negative (V_{SS}) clamp voltages, then use the larger of the two resistance values.

² All functional non-supply pins are internally clamped to V_{SS} and V_{DD} .

- ³ Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{IN} > V_{DD}$) is greater than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Ensure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power. Examples are: if no system clock is present, or if the clock rate is very low (which would reduce overall power consumption).

3.4 Thermal Characteristics

This section provides information about operating temperature range, power dissipation, and package thermal resistance. Power dissipation on I/O pins is usually small compared to the power dissipation in on-chip logic and voltage regulator circuits, and it is user-determined rather than being controlled by the MCU design. To take $P_{I/O}$ into account in power calculations, determine the difference between actual pin voltage and V_{SS} or V_{DD} and multiply by the pin current for each I/O pin. Except in cases of unusually high pin current (heavy loads), the difference between pin voltage and V_{SS} or V_{DD} will be very small.

Table 5. Thermal Characteristics

Rating		Symbol	Value	Unit
Operating temperature range (packaged)		T _A	−40 to 85	°C
Maximum junction temperature		T _{JM}	95	°C
Thermal resistance Single-layer board				
	32-pin LQFP	θ _{JA}	82	°C/W
	44-pin LQFP		68	
	48-pin QFN		81	
	64-pin LQFP	θ _{JA}	69	°C/W
	80-pin LQFP		60	
Thermal resistance Four-layer board				
	32-pin LQFP	θ _{JA}	54	°C/W
	44-pin LQFP		46	
	48-pin QFN		26	
	64-pin LQFP	θ _{JA}	50	°C/W
	80-pin LQFP		47	

The average chip-junction temperature (T_J) in °C can be obtained from:

$$T_J = T_A + (P_D \times \theta_{JA}) \quad \text{Eqn. 1}$$

where:

T_A = Ambient temperature, °C

θ_{JA} = Package thermal resistance, junction-to-ambient, °C/W

$P_D = P_{int} + P_{I/O}$

$P_{int} = I_{DD} \times V_{DD}$, Watts — chip internal power

$P_{I/O}$ = Power dissipation on input and output pins — user determined

3.6 DC Characteristics

This section includes information about power supply requirements and I/O pin characteristics.

Table 8. DC Characteristics

Num	C	Characteristic	Symbol	Condition	Min	Typ ¹	Max	Unit
1		Operating Voltage			1.8 ²		3.6	V
2	C	Output high voltage All I/O pins, low-drive strength	V _{OH}	1.8 V, I _{Load} = –2 mA	V _{DD} – 0.5	—	—	V
	P	All I/O pins, high-drive strength		2.7 V, I _{Load} = –10 mA	V _{DD} – 0.5	—	—	
	T	2.3 V, I _{Load} = –6 mA		V _{DD} – 0.5	—	—		
	C	1.8V, I _{Load} = –3 mA		V _{DD} – 0.5	—	—		
3	D	Output high current Max total I _{OH} for all ports	I _{OHT}		—	—	100	mA
4	C	Output low voltage All I/O pins, low-drive strength	V _{OL}	1.8 V, I _{Load} = 2 mA	—	—	0.5	V
	P	All I/O pins, high-drive strength		2.7 V, I _{Load} = 10 mA	—	—	0.5	
	T	2.3 V, I _{Load} = 6 mA		—	—	0.5		
	C	1.8 V, I _{Load} = 3 mA		—	—	0.5		
5	D	Output low current Max total I _{OL} for all ports	I _{OLT}		—	—	100	mA
6	P	Input high voltage all digital inputs	V _{IH}	V _{DD} > 2.7 V	0.70 x V _{DD}	—	—	V
	C	V _{DD} > 1.8 V		0.85 x V _{DD}	—	—		
7	P	Input low voltage all digital inputs	V _{IL}	V _{DD} > 2.7 V	—	—	0.35 x V _{DD}	
	C	V _{DD} > 1.8 V		—	—	0.30 x V _{DD}		
8	C	Input hysteresis all digital inputs	V _{hys}		0.06 x V _{DD}	—	—	mV
9	P	Input leakage current all input only pins (Per pin)	I _{In}	V _{In} = V _{DD} or V _{SS}	—	—	1	μA
10	P	Hi-Z (off-state) leakage current all input/output (per pin)	I _{OZ}	V _{In} = V _{DD} or V _{SS}	—	—	1	μA
11	P	Pull-up resistors all digital inputs, when enabled	R _{PU}		17.5	—	52.5	kΩ
12	D	DC injection current ^{3, 4, 5} Single pin limit	I _{IC}	V _{IN} < V _{SS} , V _{IN} > V _{DD}	–0.2	—	0.2	mA
		Total MCU limit, includes sum of all stressed pins			–5	—	5	mA
13	C	Input Capacitance, all pins	C _{In}		—	—	8	pF
14	C	RAM retention voltage	V _{RAM}		—	0.6	1.0	V
15	C	POR re-arm voltage ⁶	V _{POR}		0.9	1.4	1.79	V
16	D	POR re-arm time	t _{POR}		10	—	—	μs
17	P	Low-voltage detection threshold — high range ⁷	V _{LVDH} ⁸	V _{DD} falling V _{DD} rising	2.11 2.16	2.16 2.21	2.22 2.27	V

Table 8. DC Characteristics (continued)

Num	C	Characteristic	Symbol	Condition	Min	Typ ¹	Max	Unit
18	P	Low-voltage detection threshold — low range ⁷	V_{LVDL}	V_{DD} falling V_{DD} rising	1.80 1.86	1.82 1.90	1.91 1.99	V
19	P	Low-voltage warning threshold — high range ⁷	V_{LVWH}	V_{DD} falling V_{DD} rising	2.36 2.36	2.46 2.46	2.56 2.56	V
20	P	Low-voltage warning threshold — low range ⁷	V_{LVWL}	V_{DD} falling V_{DD} rising	2.11 2.16	2.16 2.21	2.22 2.27	V
21	C	Low-voltage inhibit reset/recover hysteresis ⁷	V_{hys}		—	50	—	mV
22	P	Bandgap Voltage Reference ⁹	V_{BG}		1.15	1.17	1.18	V

¹ Typical values are measured at 25°C. Characterized, not tested

² As the supply voltage rises, the LVD circuit will hold the MCU in reset until the supply has risen above V_{LVDL} .

³ All functional non-supply pins are internally clamped to V_{SS} and V_{DD} .

⁴ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

⁵ Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > V_{DD}$) is greater than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Ensure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power. Examples are: if no system clock is present, or if clock rate is very low (which would reduce overall power consumption).

⁶ Maximum is highest voltage that POR is guaranteed.

⁷ Low voltage detection and warning limits measured at 1 MHz bus frequency.

⁸ Run at 1 MHz bus frequency

⁹ Factory trimmed at $V_{DD} = 3.0$ V, Temp = 25°C

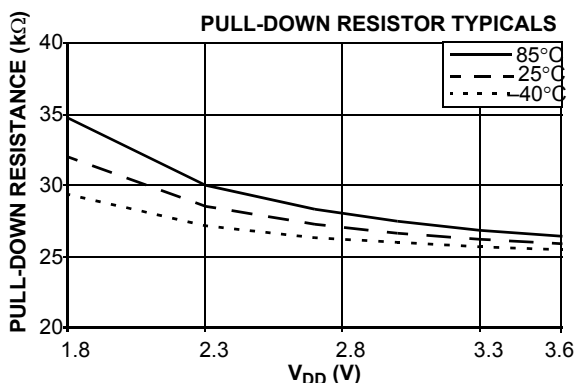
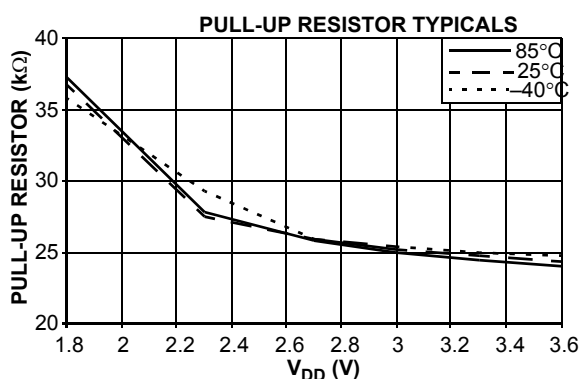


Figure 7. Pull-up and Pull-down Typical Resistor Values

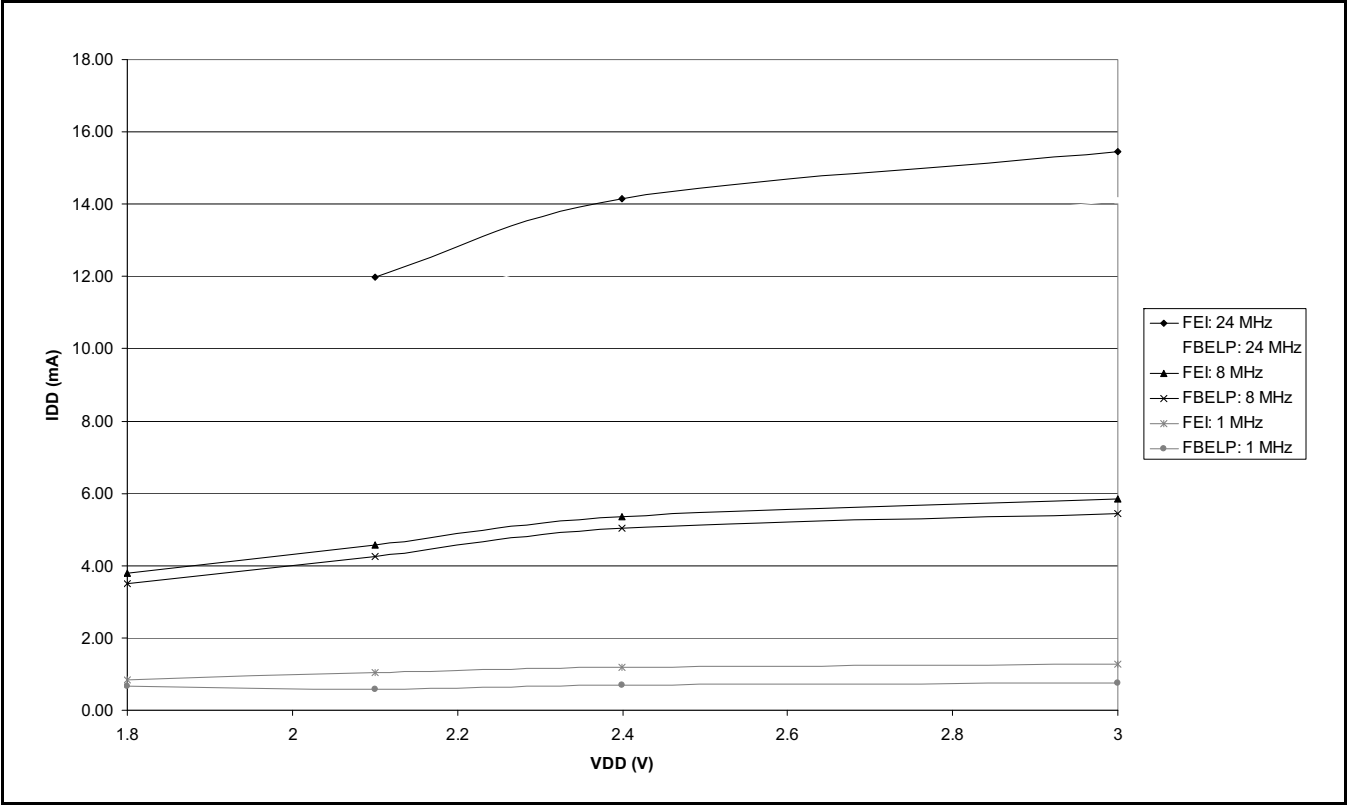
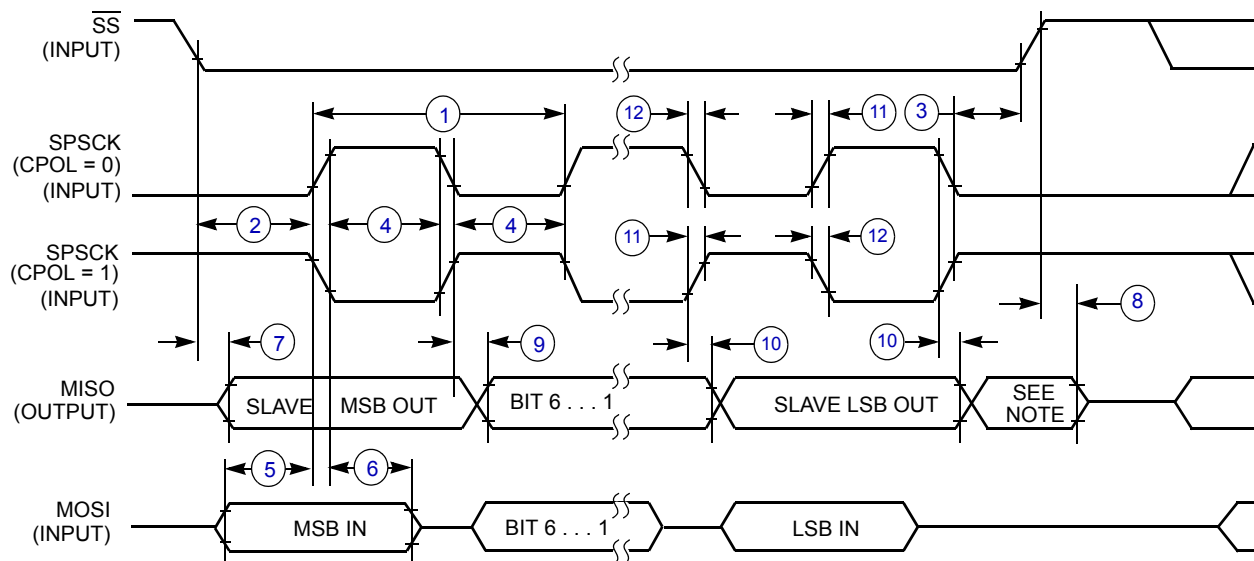


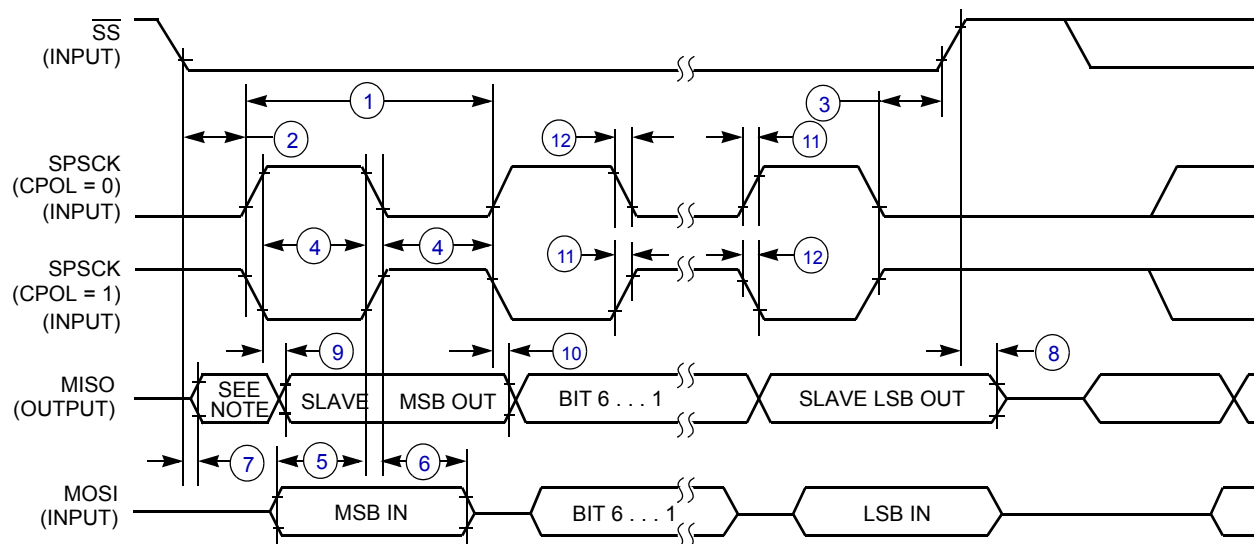
Figure 12. Typical Run I_{DD} for FBE and FEI, I_{DD} vs. V_{DD}
(ADC off, All Other Modules Enabled)



NOTE:

1. Not defined but normally MSB of character just received

Figure 23. SPI Slave Timing (CPHA = 0)



NOTE:

1. Not defined but normally LSB of character just received

Figure 24. SPI Slave Timing (CPHA = 1)

Table 18. 12-bit ADC Characteristics ($V_{REFH} = V_{DDAD}$, $V_{REFL} = V_{SSAD}$) (continued)

Characteristic	Conditions	C	Symb	Min	Typ ¹	Max	Unit	Comment
Conversion Time (Including sample time)	Short Sample (ADLSMP=0)	P	t_{ADC}	—	20	—	ADCK cycles	See the ADC chapter in the MC9S08QE128 Reference Manual for conversion time variances
	Long Sample (ADLSMP=1)	C		—	40	—		
Sample Time	Short Sample (ADLSMP=0)	P	t_{ADS}	—	3.5	—	ADCK cycles	
	Long Sample (ADLSMP=1)	C		—	23.5	—		
Total Unadjusted Error	12 bit mode	T	E_{TUE}	—	± 3.0	—	LSB ²	Includes Quantization
	10 bit mode	P		—	± 1	± 2.5		
	8 bit mode	T		—	± 0.5	± 1.0		
Differential Non-Linearity	12 bit mode	T	DNL	—	± 1.75	—	LSB ²	
	10 bit mode ³	P		—	± 0.5	± 1.0		
	8 bit mode ³	T		—	± 0.3	± 0.5		
Integral Non-Linearity	12 bit mode	T	INL	—	± 1.5	—	LSB ²	
	10 bit mode	T		—	± 0.5	± 1.0		
	8 bit mode	T		—	± 0.3	± 0.5		
Zero-Scale Error	12 bit mode	T	E_{ZS}	—	± 1.5	—	LSB ²	$V_{ADIN} = V_{SSAD}$
	10 bit mode	P		—	± 0.5	± 1.5		
	8 bit mode	T		—	± 0.5	± 0.5		
Full-Scale Error	12 bit mode	T	E_{FS}	—	± 1.0	—	LSB ²	$V_{ADIN} = V_{DDAD}$
	10 bit mode	P		—	± 0.5	± 1		
	8 bit mode	T		—	± 0.5	± 0.5		
Quantization Error	12 bit mode	D	E_Q	—	-1 to 0	—	LSB ²	
	10 bit mode			—	—	± 0.5		
	8 bit mode			—	—	± 0.5		
Input Leakage Error	12 bit mode	D	E_{IL}	—	± 2	—	LSB ²	Pad leakage ⁴ * R_{AS}
	10 bit mode			—	± 0.2	± 4		
	8 bit mode			—	± 0.1	± 1.2		
Temp Sensor Slope	-40°C to 25°C	D	m	—	1.646	—	mV/°C	
	25°C to 85°C			—	1.769	—		
Temp Sensor Voltage	25°C	D	V_{TEMP25}	—	701.2	—	mV	

¹ Typical values assume $V_{DDAD} = 3.0V$, Temp = 25°C, $f_{ADCK} = 1.0MHz$ unless otherwise stated. Typical values are for reference only and are not tested in production.

² 1 LSB = $(V_{REFH} - V_{REFL})/2^N$

³ Monotonicity and No-Missing-Codes guaranteed in 10 bit and 8 bit modes

⁴ Based on input pad leakage current. Refer to pad electricals.

3.13 Flash Specifications

This section provides details about program/erase times and program-erase endurance for the flash memory.

Program and erase operations do not require any special power sources other than the normal V_{DD} supply. For more detailed information about program/erase operations, see the Memory section of the *MC9S08QE128 Reference Manual*.

Table 19. Flash Characteristics

C	Characteristic	Symbol	Min	Typical	Max	Unit
D	Supply voltage for program/erase -40°C to 85°C	$V_{\text{prog/erase}}$	1.8		3.6	V
D	Supply voltage for read operation	V_{Read}	1.8		3.6	V
D	Internal FCLK frequency ¹	f_{FCLK}	150		200	kHz
D	Internal FCLK period (1/FCLK)	t_{Fcyc}	5		6.67	μs
P	Byte program time (random location) ⁽²⁾	t_{prog}	9			t_{Fcyc}
P	Byte program time (burst mode) ⁽²⁾	t_{Burst}	4			t_{Fcyc}
P	Page erase time ²	t_{Page}	4000			t_{Fcyc}
P	Mass erase time ⁽²⁾	t_{Mass}	20,000			t_{Fcyc}
	Byte program current ³	R_{IDDBP}	—	4	—	mA
	Page erase current ³	R_{IDDPE}	—	6	—	mA
C	Program/erase endurance ⁴ T_L to T_H = -40°C to + 85°C $T = 25^\circ\text{C}$		10,000 —	— 100,000	— —	cycles
C	Data retention ⁵	$t_{\text{D_ret}}$	15	100	—	years

¹ The frequency of this clock is controlled by a software setting.

² These values are hardware state machine controlled. User code does not need to count cycles. This information supplied for calculating approximate time to program and erase.

³ The program and erase currents are additional to the standard run I_{DD} . These values are measured at room temperatures with $V_{DD} = 3.0$ V, bus frequency = 4.0 MHz.

⁴ **Typical endurance for flash** was evaluated for this product family on the HC9S12Dx64. For additional information on how Freescale defines typical endurance, please refer to Engineering Bulletin EB619, *Typical Endurance for Nonvolatile Memory*.

⁵ **Typical data retention** values are based on intrinsic capability of the technology measured at high temperature and de-rated to 25°C using the Arrhenius equation. For additional information on how Freescale defines typical data retention, please refer to Engineering Bulletin EB618, *Typical Data Retention for Nonvolatile Memory*.

4 Ordering Information

This section contains ordering information for MC9S08QE128, MC9S08QE96, and MC9S08QE64 devices.

Table 20. Ordering Information

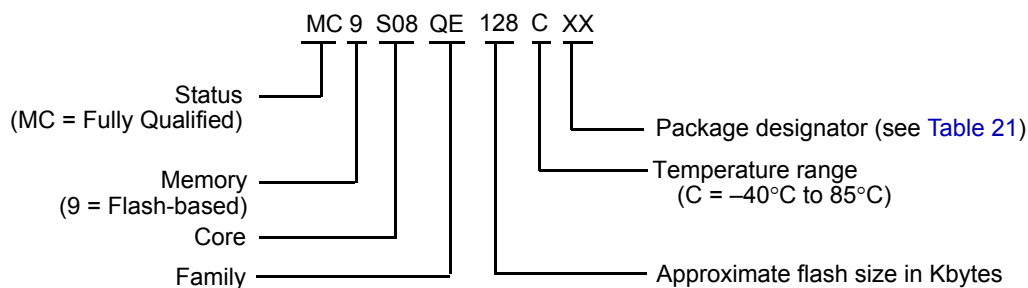
Freescale Part Number ¹	Memory		Temperature range (°C)	Package ²
	Flash	RAM		
MC9S08QE128CLK	128K	8K	-40 to +85	80 LQFP
MC9S08QE128CLH			-40 to +85	64 LQFP
MC9S08QE128CFT			-40 to +85	48 QFN
MC9S08QE128CLD			-40 to +85	44 LQFP
MC9S08QE96CLK	96K	6K	-40 to +85	80 LQFP
MC9S08QE96CLH			-40 to +85	64 LQFP
MC9S08QE96CFT			-40 to +85	48 QFN
MC9S08QE96CLD			-40 to +85	44 QFP
MC9S08QE64CLH	64K	4K	-40 to +85	64 LQFP
MC9S08QE64CFT			-40 to +85	48 QFN
MC9S08QE64CLD			-40 to +85	44 QFP
MC9S08QE64CLC			-40 to +85	32 LQFP

¹ See the reference manual, *MC9S08QE128RM*, for a complete description of modules included on each device.

² See [Table 21](#) for package information.

4.1 Device Numbering System

Example of the device numbering system:



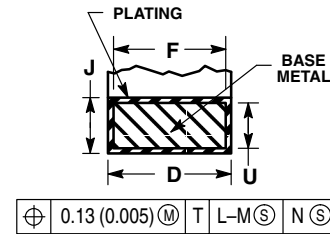
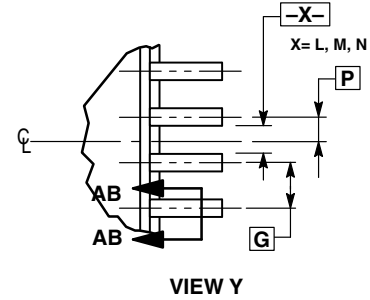
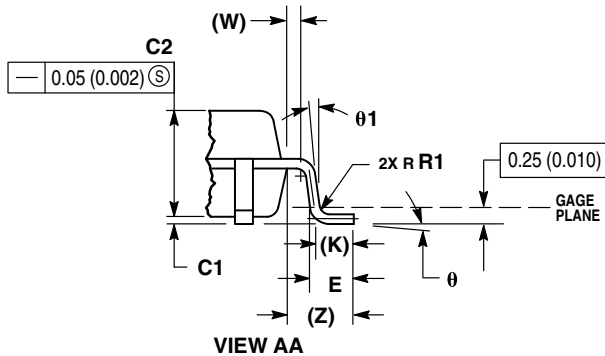
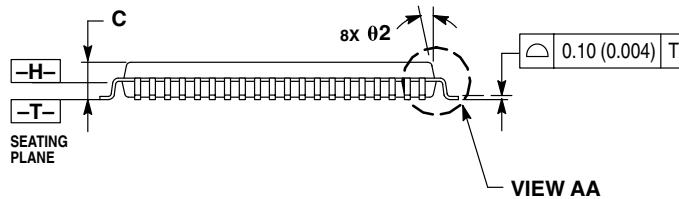
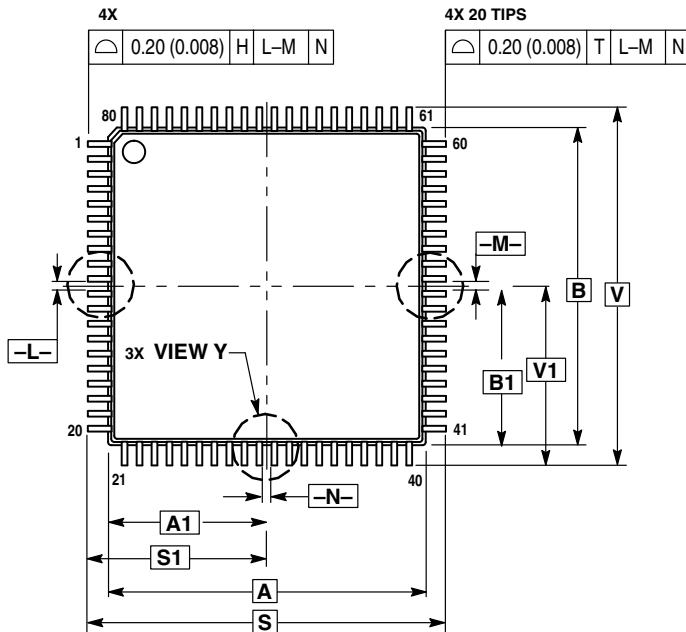
5 Package Information

The below table details the various packages available.

Table 21. Package Descriptions

Pin Count	Package Type	Abbreviation	Designator	Case No.	Document No.
80	Low Quad Flat Package	LQFP	LK	917A	98ASS23237W
64	Low Quad Flat Package	LQFP	LH	840F	98ASS23234W
48	Quad Flat No-Leads	QFN	FT	1314	98ARH99048A
44	Low Quad Flat Package	LQFP	LD	824D	98ASS23225W
32	Low Quad Flat Package	LQFP	LC	873A	98ASH70029A

Package Information



SECTION AB-AB
ROTATED 90° CLOCKWISE

NOTES:

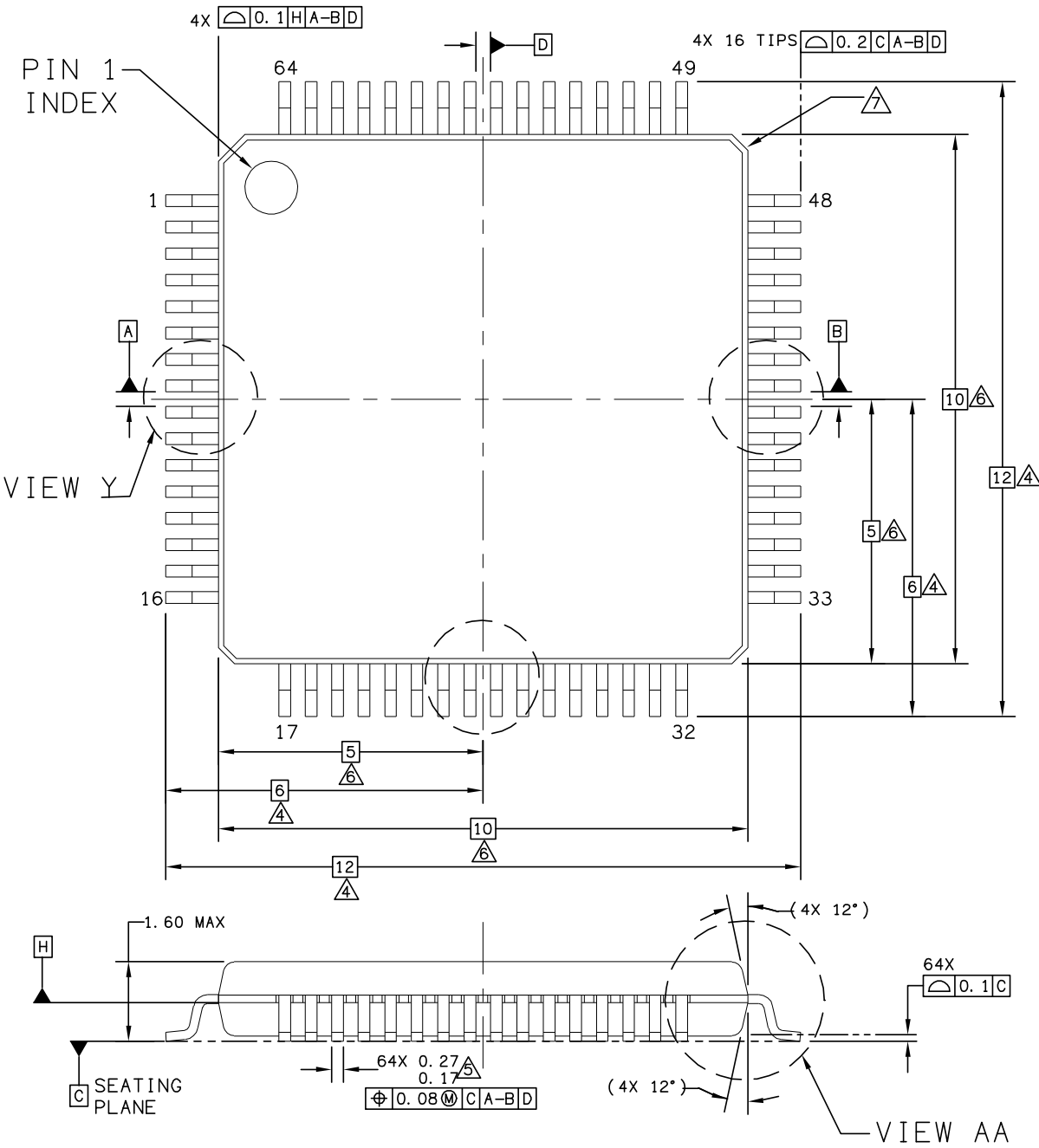
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DATUM PLANE -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
4. DATUMS -L-, -M- AND -N- TO BE DETERMINED AT DATUM PLANE -H-.
5. DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE -T-.
6. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.250 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED 0.460 (0.018). MINIMUM SPACE BETWEEN PROTRUSION AND ADJACENT LEAD OR PROTRUSION 0.07 (0.003).

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	14.00 BSC	0.551 BSC		
A1	7.00 BSC	0.276 BSC		
B	14.00 BSC	0.551 BSC		
B1	7.00 BSC	0.276 BSC		
C	—	1.60	—	0.063
C1	0.04	0.24	0.002	0.009
C2	1.30	1.50	0.051	0.059
D	0.22	0.38	0.009	0.015
E	0.40	0.75	0.016	0.030
F	0.17	0.33	0.007	0.013
G	0.65 BSC	0.026 BSC		
J	0.09	0.27	0.004	0.011
K	0.50 REF	0.020 REF		
P	0.325 BSC	0.013 REF		
R1	0.10	0.20	0.004	0.008
S	16.00 BSC	0.630 BSC		
S1	8.00 BSC	0.315 BSC		
U	0.09	0.16	0.004	0.006
V	16.00 BSC	0.630 BSC		
V1	8.00 BSC	0.315 BSC		
W	0.20 REF	0.008 REF		
Z	1.00 REF	0.039 REF		
Ø	0°	10°	0°	10°
Ø1	0°	—	0°	—
Ø2	9°	14°	9°	14°

DATE 09/21/95

CASE 917A-02
ISSUE C

Figure 26. 80-pin LQFP Package Drawing (Case 917A, Doc #98ASS23237W)



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TITLE: 64LD LQFP, 10 X 10 X 1.4 PKG, 0.5 PITCH, CASE OUTLINE		DOCUMENT NO: 98ASS23234W	REV: D
		CASE NUMBER: 840F-02	06 APR 2005
		STANDARD: JEDEC MS-026 BCD	

Figure 27. 64-pin LQFP Package Drawing (Case 840F, Doc #98ASS23234W), Sheet 1 of 3

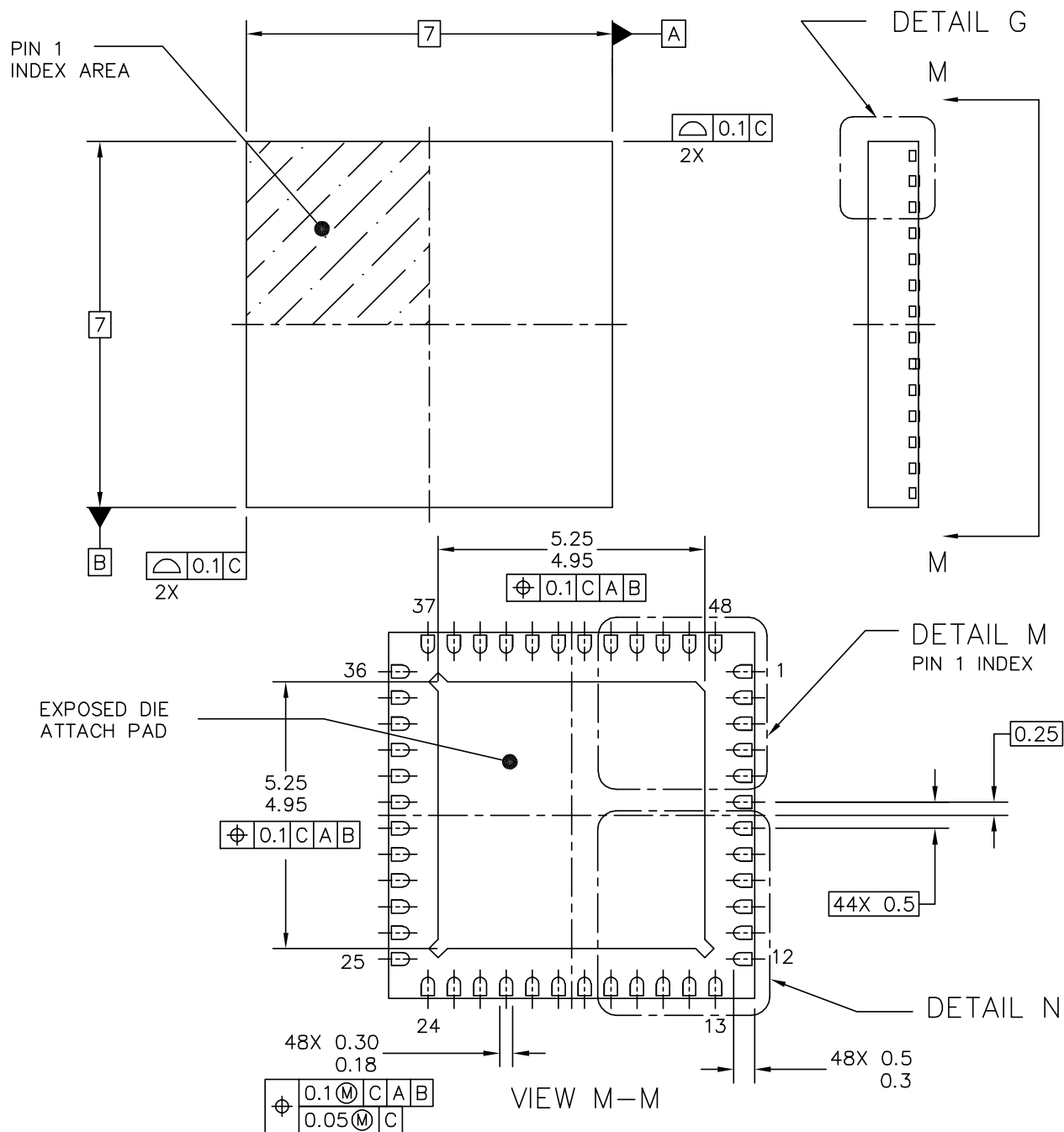
NOTES:

1. DIMENSIONS ARE IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. DATUMS A, B AND D TO BE DETERMINED AT DATUM PLANE H.
4. DIMENSIONS TO BE DETERMINED AT SEATING PLANE C.
5. THIS DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED THE UPPER LIMIT BY MORE THAN 0.08 mm AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSION AND ADJACENT LEAD SHALL NOT BE LESS THAN 0.07 mm.
6. THIS DIMENSION DOES NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 mm PER SIDE. THIS DIMENSION IS MAXIMUM PLASTIC BODY SIZE DIMENSION INCLUDING MOLD MISMATCH.
7. EXACT SHAPE OF EACH CORNER IS OPTIONAL.
8. THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.1 mm AND 0.25 mm FROM THE LEAD TIP.

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TITLE: 64LD LQFP, 10 X 10 X 1.4 PKG, 0.5 PITCH, CASE OUTLINE	DOCUMENT NO: 98ASS23234W		REV: D
	CASE NUMBER: 840F-02		06 APR 2005
	STANDARD: JEDEC MS-026 BCD		

Figure 29. 64-pin LQFP Package Drawing (Case 840F, Doc #98ASS23234W), Sheet 3 of 3

Package Information

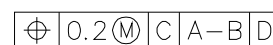


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TITLE: THERMALLY ENHANCED QUAD FLAT NON-LEADED PACKAGE (QFN) 48 TERMINAL, 0.5 PITCH (7 X 7 X 1)	DOCUMENT NO: 98ARH99048A		REV: F	
	CASE NUMBER: 1314-05		05 DEC 2005	
	STANDARD: JEDEC-MO-220 VKKD-2			

Figure 30. 48-pin QFN Package Drawing (Case 1314, Doc #98ARH99048A), Sheet 1 of 3



Figure 31. 48-pin QFN Package Drawing (Case 1314, Doc #98ARH99048A), Sheet 2 of 3



SECTION F-F

ROTATED 90°CW
32 PLACES

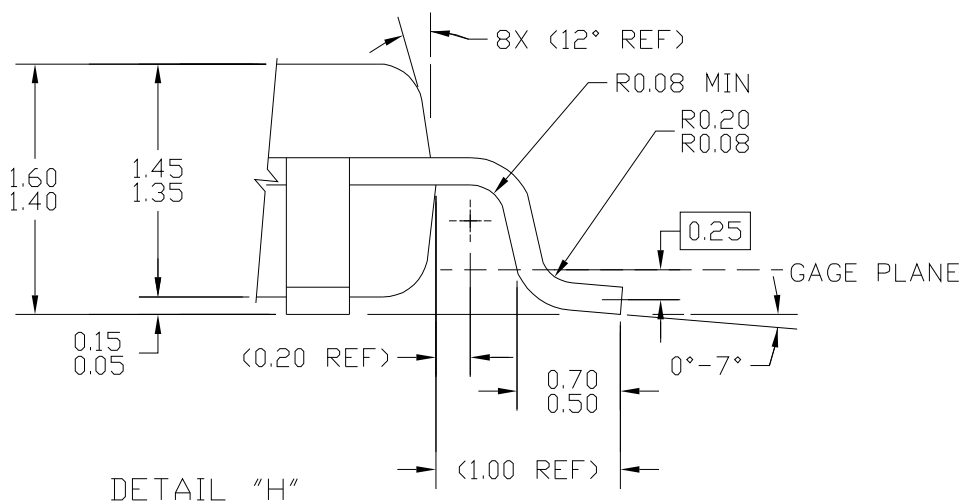


Figure 37. 32-pin LQFP Package Drawing (Case 873A, Doc #98ASH70029A), Sheet 2 of 3

Package Information

NOTES:

1. DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5–1994.
3. DATUMS A, B, AND D TO BE DETERMINED AT DATUM PLANE H.
4. DIMENSIONS TO BE DETERMINED AT SEATING PLANE DATUM C.
5. DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED THE MAXIMUM DIMENSION BY MORE THAN 0.08 MM. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSION AND ADJACENT LEAD OR PROTRUSION: 0.07 MM.
6. DIMENSIONS DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 MM PER SIDE. DIMENSIONS ARE MAXIMUM PLASTIC BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH.
7. EXACT SHAPE OF EACH CORNER IS OPTIONAL.
8. THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.1 MM AND 0.25 MM FROM THE LEAD TIP.

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TITLE: LOW PROFILE QUAD FLAT PACK (LQFP) 32 LEAD, 0.8 PITCH (7 X 7 X 1.4)	DOCUMENT NO: 98ASH70029A	REV: D
	CASE NUMBER: 873A-03	19 MAY 2005
	STANDARD: JEDEC MS-026 BBA	

Figure 38. 32-pin LQFP Package Drawing (Case 873A, Doc #98ASH70029A), Sheet 3 of 3